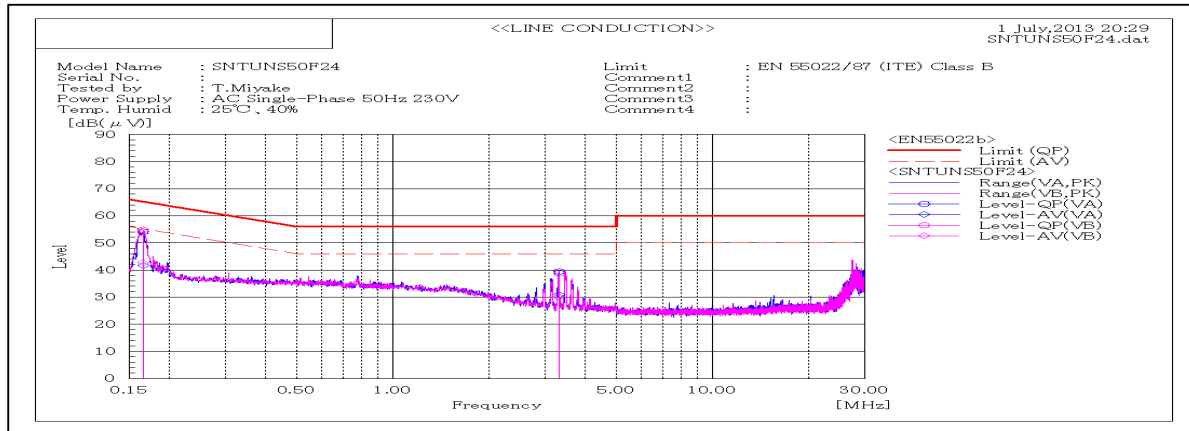
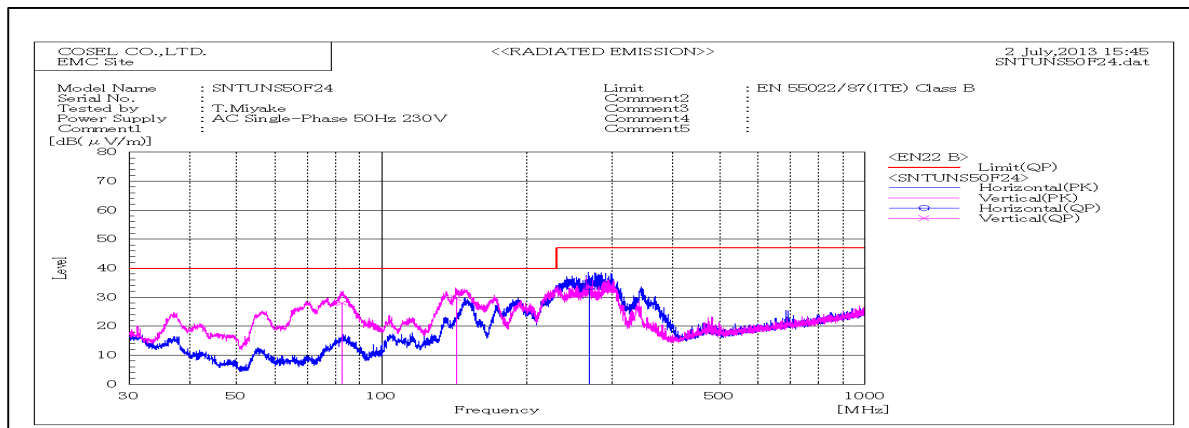


DATA SHEET		Date	19-Jul-13
Model	SNTUNS50F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



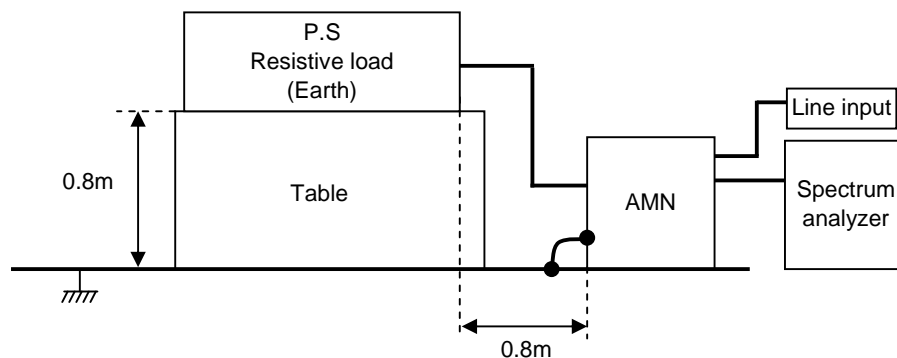
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.16547	VB	34.6	22.4	20.2	54.8	42.6	65.2	55.2	10.4	12.6	Pass	
0.16584	VA	33.9	21.4	20.2	54.1	41.6	65.2	55.2	11.1	13.6	Pass	
3.31736	VA	19	10.6	20.4	39.4	31	56	46	16.6	15	Pass	
3.31925	VB	18.3	9.7	20.4	38.7	30.1	56	46	17.3	15.9	Pass	



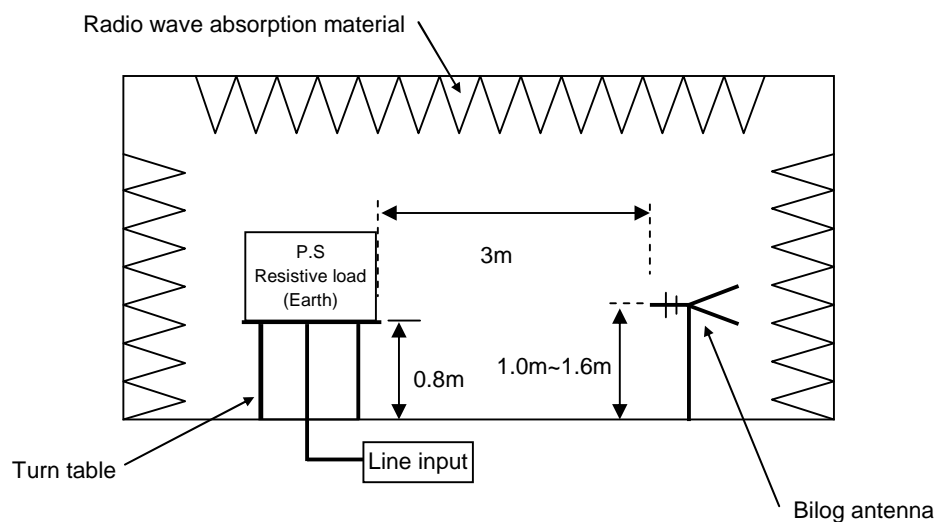
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
82.69	V	Stable	48.6	-20.6	28	40	12	Pass	115	11		
142.495	V	Stable	46.9	-17.3	29.6	40	10.4	Pass	117	52		
268.786	H	Stable	51.6	-18.1	33.5	47	13.5	Pass	106	104		

DATA SHEET		Date	19-Jul-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission



Test:EMI

Model Name: SNTUNS50F Series

○ Photographs of Test Set-Up

LINE CONDUCTION



(A) Outside of a case



(B) Inside of a case

RADIATED EMISSION



(C) Outside of a case



(D) Inside of a case